

JOURNAL OF APPLIED PROBABILITY

VOLUME 42

NUMBER 3

SEPTEMBER 2005



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JOURNAL OF APPLIED PROBABILITY

This is an international journal published by the Applied Probability Trust in association with the London Mathematical Society; it contains research papers and notes on applications of probability theory to the biological, physical, social and technological sciences. An annual volume of up to 1200 pages is published in four issues appearing in March, June, September and December.

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